# Verification of Compliance

**Product Name** 

POC-100 Series

Model Number

: POC-100RK

Applicant

: Neousys Technology Inc.

Address

: 15F, No. 868-3, Zhongzheng Rd., Zhonghe Dist.,

New Taipei City, 23586, Taiwan

Report Number

: C22-U070-1302-289

Issue Date

June 11, 2013

Applicable Standards: EN 55022:2010 Class A ITE

EN 61000-3-2: 2006+A1:2009+A2:2009

EN 61000-3-3:2008 EN 55024:2010

EN 61000-4-2:2009

EN 61000-4-3:2006+A1:2008+A2:2010

EN 61000-4-4:2004+A1:2010

EN 61000-4-5:2006 EN 61000-4-6:2009 EN 61000-4-8:2010 EN 61000-4-11:2004

Based on the EMC Directive 2004/108/EC and the specifications of the customer, one sample of the designated product has been tested in our laboratory and found to be in compliance with the EMC standards cited above.



TAF 0905

FCC CAB Code TW1053

NVLAP Lab Code 200575-0

IC Code 4699A

VCCI Accep. No. R-1527, C-1609, T-1441, G-10,

T-1334, G-10, G-614



Central Research Technology Co.

**EMC Test Laboratory** 

11, Lane 41, Fushuen St., Jungshan Chiu,

Taipei, Taiwan, 104, R.O.C.

Tel: 886-2-25984568

Fax: 886-2-25984546

(Tsun-Yu Shih/ General Manager)

Date: June 11, 2013

# **CE EMC Test Report**

for

## **POC-100 Series**

Model No. : POC-100RK

Report Number : C22-U070-1302-289

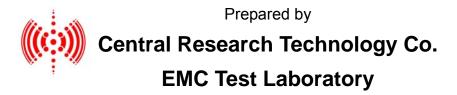
Date of Receipt: March 4, 2013

Date of Report : June 11, 2013

#### Prepared for

## **Neousys Technology Inc.**

15F, No. 868-3, Zhongzheng Rd., Zhonghe Dist., New Taipei City, 23586, Taiwan



11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C.

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# **Verification of Compliance**

**Equipment Under Test**: POC-100 Series

Model No. : POC-100RK

**Applicant**: Neousys Technology Inc.

**Address**: 15F, No. 868-3, Zhongzheng Rd., Zhonghe Dist.,

New Taipei City, 23586, Taiwan

Applicable Standards : EN 55022:2010 Class A ITE

EN 61000-3-2:2006+A1:2009+A2:2009

EN 61000-3-3:2008 EN 55024:2010 EN 61000-4-2:2009

EN 61000-4-3:2006+A1:2008+A2:2010

EN 61000-4-4:2004+A1:2010

EN 61000-4-5:2006 EN 61000-4-6:2009 EN 61000-4-8:2010 EN 61000-4-11:2004

Date of Testing : March 4~May 27, 2013

**Deviation**: The test method and configuration of EMS tests are following

the requirement of the applicable standards cited above.

Condition of Test Sample : Engineering Sample

We, **Central Research Technology Co.**, hereby certify that one sample of the designated product was tested in our facility during the period mentioned above. The test records, data evaluation and Equipment Under Test (EUT) configurations shown in the present report are true and accurate representation of the measurements of the sample's EMC characteristics under the conditions herein specified.

The test results show that the EUT as described in the present report is in compliance with the requirements set forth in the standards mentioned above and apply to the tested sample identified in the present report only. The test report shall not be reproduced, except in its entirety, without the written approval of Central Research Technology Co.

PREPARED BY : Rosa Haveh , DATE : Jane 11, 2013
(Rosa Hsieh/System Executive)

APPROVED BY: J. Y. Ul., DATE: June 11, 20/3

(Tsun-Yu Shih/General Manager)

CENTRAL RESEARCH TECHNOLOGY CO.

11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C.

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## 1. General Description

## 1.1 General Description of EUT

Equipment Under Test : POC-100 Series

Model No. : POC-100RK

Power in : Supplied by the power adapter.

Power adapter specification : Trade Name : LIEN CHANG

Model No. : LCAP07F

Input : 100-240Vac, 50-60Hz, 1.0A

Output : 12Vdc, 3.0A

Highest Operating Frequency : 1.8GHz from the test specification

Manufacturer : Neousys Technology Inc.

Function Description :

The EUT is an engineering sample of the POC-100 Series. Please refer to the user's manual for the details.

The I/O ports of EUT are listed below:

No.	I/O Port Type	Quantity
1	D-Sub port	1
2	USB port	3
3	Com. port	2
4	LAN port	2
5	Audio output port	1

## The specifications of the EUT (supplied by manufacturer) are listed below:

## POC-100 Series Specifications

System Core		Power Supply		
Processor	Intel® Atom™ D525 1.8GHz dual-core processor	DC Input	Built-in 8~25 VDC DC input	
Chipset	Intel® ICH8-M I/O Control Hub		1x 2-pin pluggable terminal block for DC input(POC-100BK)	
Graphics	Integrated Intel® GMA 3150 graphics	Input Connector	1x DC jack (ø2.5) for AC/DC adapter input(POC-100RK)	
Memory On-board soldered 2GB DDR3 800MHz SDRAM		Mechanical		
Panel I/O Inter	face	Dimension	149mm (W) x 105 mm (H) x 44 mm (D)	
Ethernet	2x Gigabit Ethernet ports by Intel® I210	Weight	1.0 kg (including one 2.5" HDD)	
Video Port	1x DB-15 connector for VGA output,	Mounting	Wall-mounting (standard) or DIN-Rail mounting (optional)	
supporting 2048 x 1536 resolution		Environmental		
Serial Port	1x software-programmable RS-232/422/485 (COM1) 1x RS-232 (COM2)	Operating Temperature	-20°C $^\sim$ 60°C with SSD or mSATA, 100% CPU loading */** -10°C $^\sim$ 50°C with HDD, 100% CPU loading */**	
USB	3x USB 2.0 ports	Storage Temperature	-40°C ~85°C	
Audio	1x Speaker-out		-40 C 85 C	
Internal I/O Int	terface	Humidity	10%~90%, non-condensing	
Seriel Port	1x optional software-programmable RS-232/422/485 (COM3) 1x optional RS-232 (COM4)	Vibration	Operating, 5 Grms, 5-500 Hz, 3 Axes (w/ SSD, w/o add-on card, according to IEC60068-2-64)	
Mini PCIe	1x mini PCI Express slot with USIM socket	Shock	Operating, 50 Grms, Half-sine 11 ms Duration	
	1x 18-bit LVDS output with backlight control,	SHOCK	(w/ SSD, w/o add-on card, according to IEC60068-2-27)	
supporting 1366 x 768 resolution		EMC	CE/FCC Class A, according to EN 55022 & EN 55024	
Storage Interface		* The CPU loading is applied using Intel® Thermal Analysis Tool. For detail testing		
SATA HDD 1x SATA ports with 2.5" HDD/SSD bracket		please contact Neousys Technology  ** For sub-zero operating temperature, a wide temperature HDD drive or Solid State		
mSATA	1x mSATA socket			

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## 1.2 Test Mode

Normal operating as the specification of manufacturer.

The EUT has 2 LAN ports. According to the preliminary test result to find that LAN 1 is worse. It was taken as the representative condition for testing and its data are recorded in the present document.

The EUT was tested with display mode: D-Sub 1024x768 @60Hz.

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## 1.3 Applied standards

According to the specifications of the manufacturer and the requirements set in European Council EMC Directive 2004/108/EC, the applied standards to evaluate the compliance of the EUT are as following:

Applied Standards	Test Items	Results
☑ EN 55022:2010 Class A ITE	Conducted Emission Measurement	<u>PASS</u>
LIV GOOZE.ZOTO GIGGOTTTE	Radiated Emission Measurement	<u>PASS</u>
☑ EN 61000-3-2:2006+A1:2009+A2:2009	Harmonic Current Emission  Measurement	<u>PASS</u>
☑ EN 61000-3-3:2008	Voltage Fluctuation and Flicker Emission Measurement	<u>PASS</u>
☑ EN 55024:2010		
☑ EN 61000-4-2:2009	Electrostatic discharge Test (ESD)	<u>PASS</u>
☑ EN 61000-4-3:2006+A1:2008+A2:2010	Radiated electromagnetic field immunity Test (RS)	<u>PASS</u>
☑ EN 61000-4-4:2004+A1:2010	Electrical fast transient / burst immunity Test (EFT)	<u>PASS</u>
☑ EN 61000-4-5:2006	Surge immunity Test	<u>PASS</u>
☑ EN 61000-4-6:2009	Immunity to conducted disturbances, induced by radio-frequency fields (CS)	<u>PASS</u>
☑ EN 61000-4-8:2010	Power frequency magnetic field immunity Test (PFM)	<u>PASS</u>
☑ EN 61000-4-11:2004	Voltage dips, short interruptions Test	<u>PASS</u>

## 1.4 Test Setup for the EUT

The EUT is an unique unit connected with other necessary accessories and support units listed in the next section. It has been tested against each standard after the following setup steps:

- a. Connect the EUT and all the support units to the appropriate power source.
- b. Turn on the EUT and all the accessories and support units.
- c. Install an EMC test software into EUT and execute it under the Windows environment.
- d. The EUT sends "H" patterns to the monitor, which fills the whole screen of it.
- e. The EUT sends messages to the modems.
- f. The EUT reads/writes messages from/to the USB 2.0 HDD/USB Flash Disk continually.
- g. The EUT sends 1kHz audio signal to the earphone.
- h. Another PC sends/ receives messages to/ from the EUT through a Hub by executing the command of "PING".
- i. Repeat and keep the setup steps listed above before and during all tests.

EUT I/O ports / Peripherals	Exerciser Program (software)	Version of Program
EUT		
Monitor		
USB 2.0 HDD/	BurnIn Test.exe	V 6.0
USB Flash Disk		
Modem		

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#### **The Support Units** 1.5

#### **Conducted Emission Test**

No.	Unit	Model No.	FCC ID	Trade Name	Power Cord	Supported by lab.
1	USB Mouse	MO56UC	DoC	DELL	N/A	<b>✓</b>
2	USB Keyboard	SK-8115	DoC	DELL	N/A	<b>~</b>
3	Monitor	U2410	DoC	DELL	1.8m	<b>✓</b>
4	USB 2.0 HDD	320G FreeAgent Go	DoC	Seagate	N/A	<b>~</b>
5	Earphone & Microphone	CW-010M.V	N/A	i-Acom	N/A	<b>~</b>
6	Modem	DM-1414	IFAXDH1414	ACEEX	1.9m	<b>√</b>

## **Radiated Emission Test**

No.	Unit	Model No.	FCC ID	Trade Name	Power Cord	Supported by lab.
1	USB Mouse	MS111-P	N/A	DELL	N/A	✓
2	USB Keyboard	KU-0355	DoC	DELL	N/A	<b>✓</b>
3	Monitor	U2410	DoC	DELL	1.8m	<b>✓</b>
4	USB 2.0 HDD	500G FreeAgent Go	DoC	Seagate	N/A	✓
5	Earphone & Microphone	EPM-662	N/A	i-gota	N/A	✓
6	Modem	DM-1414	IFAXDH1414	ACEEX	1.9m	<b>✓</b>

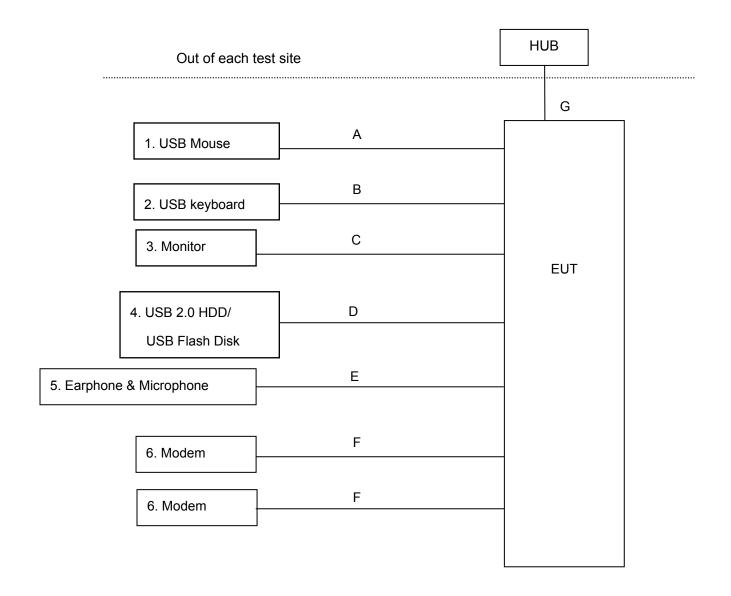
## EN 61000-3-2, EN 61000-3-3 and EMS Tests(excluding ESD Test)

No.	Unit	Model No.	FCC ID	Trade Name	Power Cord	Supported by lab.
1	USB Mouse	MO56UC	N/A	DELL	N/A	✓
2	USB Keyboard	SK-8115	DoC	DELL	N/A	<b>✓</b>
3	Monitor	2408WFP	DoC	DELL	1.8m	<b>✓</b>
4	USB Flash Disk	U172	DoC	PQI	N/A	<b>✓</b>
5	Earphone & Microphone	CW-010M.V	N/A	i-Acom	N/A	<b>✓</b>
6	Modem	DM-1414	IFAXDH1414	ACEEX	1.9m	<b>✓</b>

### **ESD Test**

No.	Unit	Model No.	FCC ID	Trade Name	Power Cord	Supported by lab.
1	USB Mouse	MO56UC	N/A	DELL	N/A	<b>✓</b>
2	USB Keyboard	SK-8115	DoC	DELL	N/A	<b>✓</b>
3	Monitor	2408WFP	DoC	DELL	1.8m	<b>✓</b>
4	USB 2.0 HDD	F12-UF	DoC	TeraSys	N/A	<b>✓</b>
5	Earphone & Microphone	CW-010M.V	N/A	i-Acom	N/A	<b>✓</b>
6	Modem	DM-1414	IFAXDH1414	ACEEX	1.9m	<b>✓</b>

## 1.6 Layout of the Setup



# **Connecting Cables:**

No.	Cable	Length	Shielded	Core	Shielded Backshell	Supported by lab.	Note
Α	USB Mouse Cable	1.8m	✓			✓	
В	USB Keyboard Cable	2.0m	✓			✓	
С	VGA Cable	1.7m	✓	✓		✓	2Cores
D	USB Cable	1.2m	✓			✓	
Е	Earphone & Microphone Cable	1.8m	<b>✓</b>			✓	
F	Modem Cable	1.8m	✓	✓		✓	2Cores
G	LAN Cable	>3m				✓	floating

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# 1.7 Test Capability

## **Test Facility**

The test facility used for evaluating the conformance of the EUT with each standard in the present report meets what required in CISPR16-1-4, CISPR16-2-3.

Test Room	Type of Test Room	Descriptions
TR1	10m semi-anechoic chamber (23m×14m×9m)	Complying with the NSA and the site VSWR requirements in documents CISPR 22 and
TR1	3m fullly-anechoic chamber (23m×14m×9m)	CISPR 16-1-4 for the radiated emission measurement.
TR11	3m semi-anechoic chamber (9m×6m×6m)	Complying with the NSA requirements set in documents CISPR 22/ EN 55022 for the radiated emission measurement.
TR5	Shielding Room (8m×5m×4m)	For the conducted emission measurement.
TR4	Shielding Room (5m×3m×3m)	To the conducted emission measurement.
TR2	3m fully-anechoic chamber (7m×3m×3m)	Complying with the field uniformity requirements in standard IEC/ EN 61000-4-3 for the radiated immunity test.
TR7	Shielding Room (5m×3m×3m)	
TR8	Shielding Room (5m×3m×3m)	For the Current Harmonic / Voltage Flicker
AR	Shielding Room (3m×3m×3m)	and other immunity tests.
TR12	Plane Grounding Site (2.4m×3m)	
TR300	3m fully-anechoic chamber (8m×5m×5m)	Complying with the site VSWR requirements set in documents CISPR 16-1-4 for the radiated emission measurement.

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## **Test Laboratory Competence Information**

Central Research Technology Co. has been accredited / filed / authorized by the agencies listed in the following table.

Certificate	Nation	Agency	Code	Mark	
	USA	NVLAP	200575-0	ISO/IEC 17025	
	R.O.C.	TAF	0905	ISO/IEC 17025	
	(Taiwan)	IAI	0903	130/1LC 17023	
Accreditation			SL2-IN-E-0033,		
Certificate	R.O.C.		SL2-IS-E-0033,		
		BSMI	SL2-R1/R2-E-0033,	ISO/IEC 17025	
	(Taiwan)		SL2-A1-E-0033,		
			SL2-L1-E-0033		
	USA	FCC	474046,TW1053	Test facility list	
	USA	FCC	474040,1 00 1055	& NSA Data	
Site Filing	Canada	IC	4699A-1,-3	Test facility list	
Document	Cariaua	10	4099A-1,-3	& NSA Data	
	lonon	VCCI	R-1527,C-1609, C-4400,	Test facility list	
	Japan	VCCI	T-1441, T-1334, G-10, G-614	& NSA Data	
Authorization	Germany	TUV	10021687	ISO/IEC 17025	
Certificate	Norway	Nemko	ELA 212	ISO/IEC 17025	

The copy of each certificate can be downloaded from our web site: www.crc-lab.com

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### 2. Conducted Emission Measurement

Test Result : PASS

## 2.1 Limits for Emission Measurement

## ☑ Limits for conducted disturbances at the power mains

Frequency (MHz)	Class A E	quipment	Class B Equipment		
	Quasi-peak	Average	Quasi-peak	Average	
(1711 12)	(dBµV)	(dBµV)	(dBµV)	(dBµV)	
0.15 to 0.5	79	66	66 – 56	56 – 46	
0.5 to 5	73	60	56	46	
5 to 30	73	60	60	50	

Note 1- The lower limit shall apply at the transition frequency.

Note 2- The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.5MHz for Class B equipment.

# ☑ Limits for conducted common mode disturbances at telecommunication ports

	С	lass A E	quipme	nt	Class B Equipment			
Frequency	Voltage	e Limits	Current Limits		Voltage Limits		Current Limits	
(MHz)	Q.P.	Average	Q.P.	Average	Q.P.	Average	Q.P.	Average
	(dBµV)	(dBµV)	(dBµA)	(dBµA)	(dBµV)	(dBµV)	(dBµA)	(dBµA)
0.15 to 0.5	97 - 87	84 – 74	53 – 43	40 – 30	84 – 74	74 - 64	40 – 30	30 - 20
0.5 to 30	87	74	43	30	74	64	30	20

Note 1- The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.5MHz.

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Note 2- The current and voltage disturbance limits are derived for use with an impedance stabilization network (ISN) which presents a common mode (asymmetric mode) impedance of  $150\Omega$  to the telecommunication port under test.

## 2.2 Test Instruments

Test Site and	Manufacturar	Model No./	Last	Calibration	
Equipment	Manufacturer	Serial No.	<b>Calibration Date</b>	Due Date	
Test Receiver	R&S	ESCS 30/	lon 14 2012	lon 14 2014	
rest Receiver	Ras	836858/021	Jan. 14, 2013	Jan. 14, 2014	
LISN	R&S	ESH2-Z5/	June 5, 2012	June 5, 2013	
LIGIN	ΙλάΟ	836613/001	June 3, 2012	Julie 3, 2013	
2 <sup>nd</sup> LISN	R&S	ENV4200/	March 29, 2013	March 29, 2014	
2 LIGIN	πασ	833209/010	Watch 29, 2013	Water 29, 2014	
	FCC	☐ FCC-TLISN-T2-02/	August 8, 2012	August 8, 2013	
	1 00	20269	August 0, 2012	August 0, 2013	
Balanced	FCC	☐ FCC-TLISN-T4-02/	April 1, 2013	April 1, 2014	
TELE. ISN	100	20270	Αριιι 1, 2010	Αριιι 1, 2014	
	FCC	☑ FCC-TLISN-T8-02/	Dec. 28, 2012	Dec. 28, 2013	
	100	20318	DCC. 20, 2012		
Capacitive	FCC	F-CVP-1/	Aug. 18, 2012	Aug. 18, 2013	
☐ Voltage Probe	FCC	84	Aug. 10, 2012	Aug. 10, 2013	
Broadband	A.I.I.	BCP-511/	A 40, 0040	A 40 0040	
Current Probe	AH	769	Aug. 18, 2012	Aug. 18, 2013	
FOO terminator	N/A	N/A/	Aug 20 2012	A 20 2042	
50Ω terminator	IN/A	001	Aug. 20, 2012	Aug. 20, 2013	
RF Switch	R&S	RSU28/	Feb. 19, 2013	Aug. 19, 2013	
IXI SWILCII	ΙλάΟ	338965/002	1 60. 19, 2013	Aug. 19, 2013	
RF Cable	N/A	N/A/	Feb. 19, 2013	Δυα 10 2013	
TAI Cable	IN/A	C0052 ~ 56	1 60. 19, 2013	Aug. 19, 2013	
Test Software	Audix	e3/	NCR	NCR	
		Ver. 5.2004-2-19k	11011	11011	
TR5	ETS	TR5/	NCR	NCR	
shielded room	LINDGREN	15353-F	14014	11011	

#### Note:

1. The calibrations are traceable to NML/ROC.

2. NCR: No Calibration Required.

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## **Measurement Uncertainty**

The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than  $U_{cispr}$  in table 1 of CISPR 16-4-2.

Equipment	Model Number	Uncertainty Value		
LISN	ESH2-Z5	3.1dB		
LION	ENV 4200	2.7dB		
	FCC-TLISN-T2-02	3.4dB		
ISN	FCC-TLISN-T4-02	3.2dB		
	FCC-TLISN-T8-02	3.2dB		

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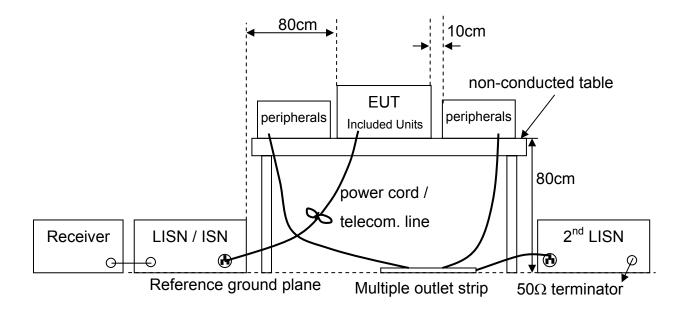
#### **Test Procedures** 2.3

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters above the reference ground plane and 0.4 meters from the conducting wall of the shielded room. Also if the EUT is floor-standing equipment, it was placed on a non-conducted support with a height up to 0.15 meters above the reference ground plane.
- c. Connect the EUT's power source / telecommunication lines to the appropriate power mains / peripherals through the LISN / ISN.
- d. All the other peripherals are connected to the 2<sup>nd</sup> LISN, if any.
- e. The LISN / ISN was placed 0.8 meters from the EUT and at least 0.8 meters from other units and other metal planes.
- f. Measure the conducted emissions on each power line (Neutral Line and Line 1 Hot side) of the EUT's power source by using the test receiver connected to the coupling RF output port of LISN.
- g. Rapidly scan the signal from 150kHz to 30MHz by using the receiver through the Maximum-Peak detector to determine those frequencies associated with higher emission levels for each measured line.
- h. Then measure the maximum level of conducted disturbance for each frequency found from step g. by using the receiver through the Quasi-Peak and Average detectors per CISPR 16-1.
- i. Record the level for each frequency and compare with the required limit.
- If required, measure the conducted emissions on telecommunication lines of EUT by using the test receiver connected to the coupling RF output port of ISN and repeat step g. to i.
- k. If the peak emission level is lower than the specified Average limit, then the emission values presented will be the peak value only. Otherwise, accurate Q.P. or Average values will be measured and presented.

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## 2.4 Test Configurations



## 2.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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### 2.6 Test Results

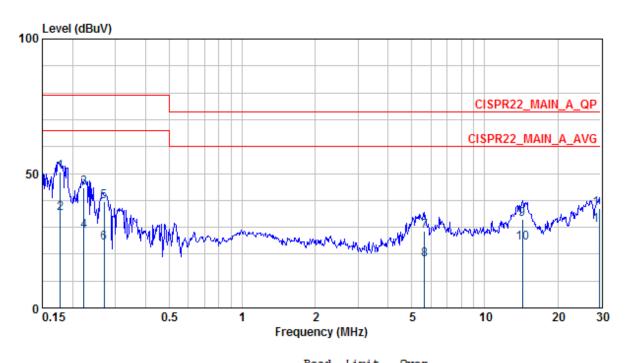
Test Mode : Normal

**Test Voltage**: 230V/50Hz to the power adapter

**Tester**: Mathew **Temperature**: 25°C

Humidity: 71%RH Frequency Range: 150kHz~30MHz

IF Bandwidth: 9kHz Phase : Line



				Kead	Limit	uver		
	Freq	Level	Factor	Level	Line	Limit	Pol/Phase	Remark
	MHz	dBuV	dB	dBuV	dBuV	dB		
1	0.178	50.68	0.28	50.40	79.00	-28.32	LINE	QP
2	0.178	35.27	0.28	34.99	66.00	-30.73	LINE	AVERAGE
3	0.222	44.64	0.29	44.35	79.00	-34.36	LINE	QP
4	0.222	28.56	0.29	28.27	66.00	-37.44	LINE	AVERAGE
5	0.269	39.50	0.30	39.20	79.00	-39.50	LINE	QP
6	0.269	24.28	0.30	23.98	66.00	-41.72	LINE	AVERAGE
7	5.653	28.72	0.54	28.18	73.00	-44.28	LINE	QP
8	5.653	17.97	0.54	17.43	60.00	-42.03	LINE	AVERAGE
9	14.288	32.96	0.69	32.27	73.00	-40.04	LINE	QP
10	14.288	24.02	0.69	23.33	60.00	-35.98	LINE	AVERAGE
11	29.684	36.91	0.23	36.68	73.00	-36.09	LINE	QP
12	29.684	30.81	0.23	30.58	60.00	-29.19	LINE	AVERAGE

#### Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.
- 4. If the limit for the measurement with the average detector is met when using a receiver with a quasi-peak detector, the EUT shall be deemed to meet both limits.

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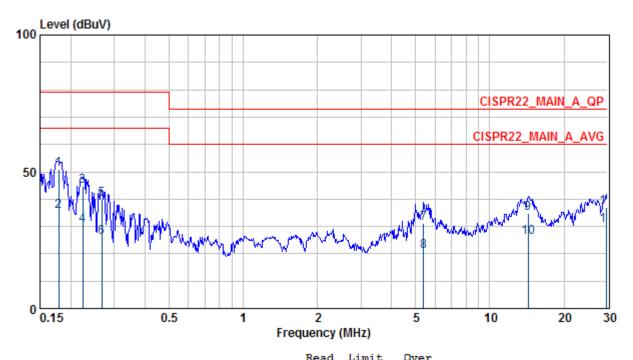
Test Mode : Normal

**Test Voltage**: 230V/50Hz to the power adapter

**Tester**: Mathew **Temperature**: 25°C

Humidity: 71%RH Frequency Range: 150kHz~30MHz

IF Bandwidth: 9kHz Phase: Neutral



				Read	PTHIT	over		
	Freq	Level	Factor	Level	Line	Limit	Pol/Phase	Remark
	MHz	dBuV	dB	dBuV	dBuV	dB		
1	0.179	50.93	0.17	50.76	79.00	-28.07	NEUTRAL	QP
2	0.179	35.58	0.17	35.41	66.00	-30.42	NEUTRAL	AVERAGE
3	0.223	44.80	0.17	44.63	79.00	-34.20	NEUTRAL	QP
4	0.223	30.28	0.17	30.11	66.00	-35.72	NEUTRAL	AVERAGE
5	0.267	39.99	0.18	39.81	79.00	-39.01	NEUTRAL	QP
6	0.267	25.92	0.18	25.74	66.00	-40.08	NEUTRAL	AVERAGE
7	5.393	31.31	0.46	30.85	73.00	-41.69	NEUTRAL	QP
8	5.393	20.97	0.46	20.51	60.00	-39.03	NEUTRAL	AVERAGE
9	14.288	34.71	0.91	33.80	73.00	-38.29	NEUTRAL	QP
10	14.288	26.11	0.91	25.20	60.00	-33.89	NEUTRAL	AVERAGE
11	29.684	36.87	1.32	35.55	73.00	-36.13	NEUTRAL	QP
12	29.684	30.42	1.32	29.10	60.00	-29.58	NEUTRAL	AVERAGE

#### Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.
- If the limit for the measurement with the average detector is met when using a receiver with a quasi-peak detector, the EUT shall be deemed to meet both limits.

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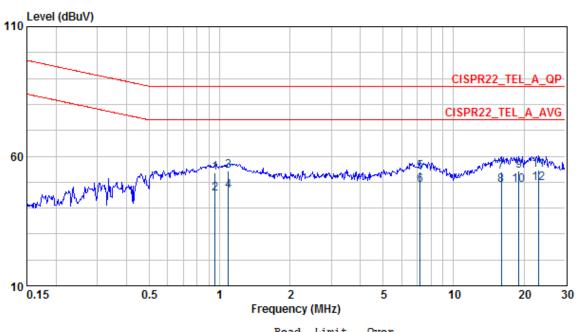
Test Mode : Normal

**Test Voltage**: 230V/50Hz to the power adapter

**Tester**: Mathew **Temperature**: 25°C

Humidity: 71%RH Frequency Range: 150kHz~30MHz

IF Bandwidth: 9kHz Phase : LAN1 for 1Gbps



				Read	Limit	Over		
	Freq	Level	Factor	Level	Line	Limit	Pol/Phase	Remark
	MHz	dBuV	dB	dBuV	dBuV	dB		
1	0.958	53.54	10.15	43.39	87.00	-33.46	LINE	QP
2	0.958	45.63	10.15	35.48	74.00	-28.37	LINE	AVERAGE
3	1.088	54.21	10.15	44.06	87.00	-32.79	LINE	QP
4	1.088	46.81	10.15	36.66	74.00	-27.19	LINE	AVERAGE
5	7.213	53.96	10.39	43.57	87.00	-33.04	LINE	QP
6	7.213	48.74	10.39	38.35	74.00	-25.26	LINE	AVERAGE
7	15.970	54.04	10.51	43.53	87.00	-32.96	LINE	QP
8	15.970	48.84	10.51	38.33	74.00	-25.16	LINE	AVERAGE
9	19.021	54.34	10.53	43.81	87.00	-32.66	LINE	QP
10	19.021	48.98	10.53	38.45	74.00	-25.02	LINE	AVERAGE
11	23.018	54.72	10.57	44.15	87.00	-32.28	LINE	QP
12 @	23.018	49.58	10.57	39.01	74.00	-24.42	LINE	AVERAGE

#### Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + insertion loss of LISN/ISN.
- Q.P. is abbreviation of guasi-peak.
- 4. If the limit for the measurement with the average detector is met when using a receiver with a quasi-peak detector, the EUT shall be deemed to meet both limits.

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## 3. Radiated Emission Measurement

Test Result : PASS

#### 3.1 Limits for Emission Measurement

Type of EUT	Highest frequency generated or used in the device or on which the device operates or tunes (MHz)	Upper frequency of measurement range (MHz)
	Below 108	1000
	108 - 500	2000
	500 - 1000	5000
		5 <sup>th</sup> harmonic of the highest
$\overline{\mathbf{A}}$	Above 1000	frequency or 6GHz,
		whichever is lower

## ☑ Limits for radiated disturbances at a measuring distance of 10m

Frequency	Class A Equipment	Class B Equipment		
(MHz)	Quasi-peak (dBμV/m)	Quasi-peak (dBμV/m)		
30 to 230	40	30		
230 to 1000 47		37		

Note 1- The lower limit shall apply at the transition frequency.

Note 2- Additional provisions may be required for cases where interference occurs.

## ☑ Limits for radiated disturbances at a measuring distance of 3m

Frequency	Class A E	quipment	Class B Equipment			
(GHz)	Peak (dBµV/m)	Average (dBµV/m)	Peak (dBµV/m)	Average (dBµV/m)		
1 to 3	76	56	70	50		
3 to 6	80	60	74	54		
Note 1- The lower limit shall apply at the transition frequency.						

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## 3.2 Test Instruments

## **☑** Below 1GHz measurement

Test Site and	Manufacturer		Last	Calibration		
Equipment		Serial No.	Calibration Date	Due Date		
EMI Test	R&S	ESCS 30/	Sept. 10, 2012	Sept. 10, 2013		
Receiver	NGO	836858/020	OCPt. 10, 2012			
Broadband	R&S	HL-562/	March 20, 2012	March 29, 2014		
Antenna	Ras	360543/007	March 29, 2013			
Broadband	Dac	HL-562/	A	A! 20 004.4		
Antenna	R&S	830547/010	April 30, 2013	April 30, 2014		
Dro Amplifior	Mini Cirouit	ZKL-2/	lon 15 2012	July 15, 2012		
Pre-Amplifier	Mini Circuit	001	Jan. 15, 2013	July 15, 2013		
D 4 115	14: : 0: ::	ZKL-2/	Jan. 15, 2013	July 15, 2013		
Pre-Amplifier	Mini Circuit	002	Jan. 15, 2015			
Spectrum		FSP7/		June 13, 2013		
Analyzer	R&S	100108	June 13, 2012			
,						
Spectrum	R&S	FSP7/	Jan. 10, 2013	Jan. 10, 2014		
Analyzer		100384	,			
RF Cable	JYEBAO	0214/	Jan. 15, 2013	July 15, 2013		
Tri Gabic	TILDAO	C0049	,	,,		
RF Cable	JYEBAO	0214/	Jan. 15, 2013	July 15, 2013		
KF Cable	JIEBAO	C0050	0dii. 10, 2010			
Test Software	Audix	e3/	NCR	NCR		
rest Software	Audix	Ver. 4.3.714.e	NUK	NCK		
TR1 Semi -	ETS.			May 4, 2014		
anechoic Chamber	LINDGREN	TR1/ 17627-B	May 4, 2013			

#### Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.
- 3. The calibration date of the chamber TR1 listed above is the date of NSA measurement.

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## **☑** Above 1GHz measurement

Test Site and Equipment	Manufacturer		Model No./ Serial No.				
Horn Antenna	EMCO	3117/ 00082847		March 5, 2013	March 5, 2014		
Bore-sight Antenna Mast	Sunol		TLT2/ 051110-5		NCR		
	KMIC		KMA010180A01/ 99056	Oct. 19, 2012	Oct. 19, 2013		
Pre-Amplifier	MITEQ	☑	JS4-00101800- 28-5A /742229	Dec. 14, 2012	Dec. 14, 2013		
			JS4-00101800- 28-5A/742309	Dec. 14, 2012	Dec. 14, 2013		
Spectrum Analyzer	R&S		FSP40/ 100031	July 11, 2012	July 11, 2013		
RF Cable	Suhner	Sucoflex 106P / C0091 + C0092 e3/ Ver. 4.3.714.e TR1/ 17627-B		April 17, 2013	Oct. 17, 2013		
Test Software	Audix					NCR	NCR
TR1 Fully - anechoic Chamber	ETS. LINDGREN			TR1/ 17627-B		Feb. 23, 2013	Feb. 23, 2014

#### Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.
- The calibration date of the chamber TR1 listed above is the date of site VSWR measurement.

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## **Measurement Uncertainty**

The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than  $U_{cispr}$  in table 1 of CISPR 16-4-2.

Test Site	Polarization	Frequency Range				
(Measuring distance)	1 Glarization	30MHz ~200MHz	200MHz ~1000MHz			
TR1(10m)	Horizontal	3.2dB	3.5dB			
TKI(10III)	Vertical	3.3dB	3.6dB			

Test Site	Polarization	Frequency Range				
(Measuring distance)	1 Glarization	1GHz ~6GHz				
TR1(3m)	Horizontal	3.7dB				
11(1(3111)	Vertical	3.7dB				
TD200(2m)	Horizontal	3.9dB				
TR300(3m)	Vertical	3.8dB				

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### 3.3 Test Procedures

## **Below 1GHz measurement**

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters above the reference ground plane and 10 meters away from the interference receiving antenna in the semi-anechoic chamber.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height up to 0.15 meters above the reference ground plane and 10 meters away from the interference-receiving antenna in the semi-anechoic chamber.
- d. Rapidly sweep the signal from 30MHz to 1GHz by using the spectrum through the Maximum-peak detector.
- e. Rotate the EUT from 0° to 360° and position the receiving antenna at heights from 1 to 4 meters above the reference ground plane continuously to determine at least six frequencies associated with higher emission levels and record them.
- f. Then measure each frequency found from step e. by using the spectrum with rotating the EUT and positioning the receiving antenna height to determine the maximum level.
- g. Finely tune the antenna and turntable around the recorded position of each frequency found from step f. by using the receiver through the Quasi-Peak detector per CISPR 16-1 to find out where the maximum level occurred.
- h. Record frequency, azimuth angle of the turntable, height, and polarization of the receiving antenna and compare the maximum level with the required limit.
- i. Change the receiving antenna to another polarization to measure radiated emission by following step d. to h. again.
- j. If the peak emission level measured from step e. is 4dB lower than the limit specified, then the emission values presented will be the peak value only. Otherwise, accurate Q.P. value will be measured and presented.

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#### **Above 1GHz measurement**

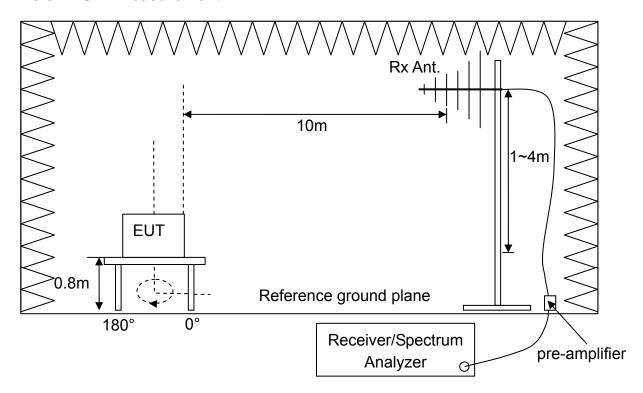
- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it should be placed on a non-conducted table with a height of 0.8 meters above the reference ground plane and 3 meters away from the interference receiving antenna in the fully-anechoic chamber.
- c. If the EUT is floor-standing equipment, it should be placed on a non-conducted support with a height up to 0.15 meters above the reference ground plane and 3 meters away from the interference-receiving antenna in the fully-anechoic chamber.
- d. Rapidly sweep the signal from 1GHz to the upper frequency of measurement range by using the spectrum through the Maximum-peak detector.
- e. Rotate the EUT from 0° to 360° continuously and position the receiving antenna at specified height above the reference ground plane to determine the frequencies associated with higher emission levels and record them.
- f. Then measure each frequency found from step e. by using the spectrum with rotating the EUT to determine the maximum peak and average level.
- g. Record frequency, azimuth angle of the turntable and compare the maximum level with the required limit.
- h. Change the receiving antenna to another polarization to measure radiated emission by following step d. to g. again.

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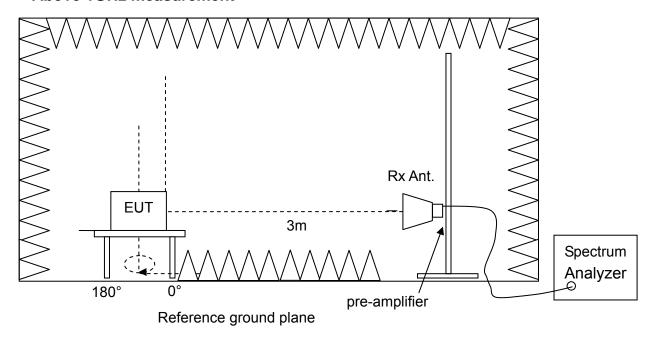
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## 3.4 Test Configurations

#### **Below 1GHz measurement**



#### **Above 1GHz measurement**



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# 3.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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#### 3.6 Test Results

#### Radiated Emission Measurement below 1000MHz

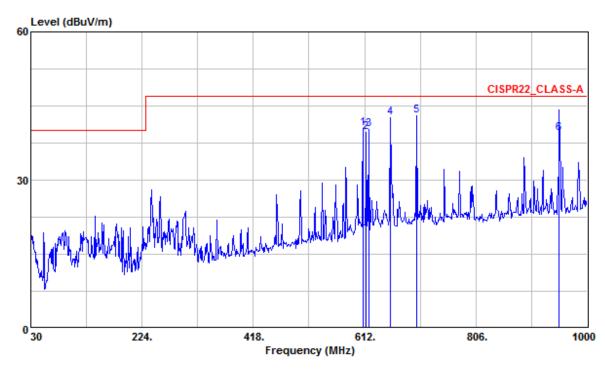
Test Mode : Normal

**Test Voltage**: 230V/50Hz to the power adapter

**Tester**: Carl **Temperature**: 25°C

Humidity: 69%RH Frequency Range: 30MHz~1GHz

**IF Bandwidth** : 120kHz **Polarization** : **Horizontal** 



			Freq	Level	Read Level	Factor	Limit Line	Over Limit		Table Pos	Pol/Phase	Remark
			MHz	dBuV/m	dBuV	dB/m	dBuV/m	dB	cm	deg		
1	@	6	09.090	40.40	48.67	-8.27	47.00	-6.60			HORIZONTAL	Peak
2	@	6	14.910	39.59	47.76	-8.17	47.00	-7.41			HORIZONTAL	Peak
3	@	6	18.790	40.17	48.29	-8.12	47.00	-6.83			HORIZONTAL	Peak
4	@	6	57.590	42.59	50.16	-7.57	47.00	-4.41			HORIZONTAL	Peak
5	@	7	02.210	42.94	50.08	-7.14	47.00	-4.06			HORIZONTAL	Peak
6	@	9	50.400	39.49	43.15	-3.66	47.00	-7.51	135	181	HORIZONTAL	QP

#### Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.
- 3. Q.P is abbreviation of quasi-peak.

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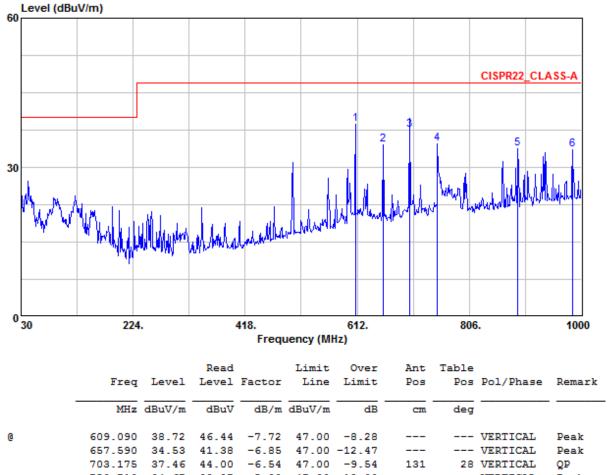
**Test Mode** Normal

**Test Voltage** 230V/50Hz to the power adapter

**Tester** Carl **Temperature** 25°C

**Humidity** 69%RH **Frequency Range** 30MHz~1GHz

IF Bandwidth: 120kHz **Polarization Vertical** 



1 @	657.590	34.53	41.38	-6.85	47.00	-12.47	 	VERTICAL VERTICAL	Peak
3 4	703.175 750.710							VERTICAL VERTICAL	~
5 6	890.390 984.480							VERTICAL VERTICAL	

#### Note:

- 1. Emission Level = reading value + correction factor.
- Correction factor = cable loss + antenna factor gain of pre-amplifier.
- Q.P is abbreviation of quasi-peak.

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#### Radiated Emission Measurement above 1000MHz

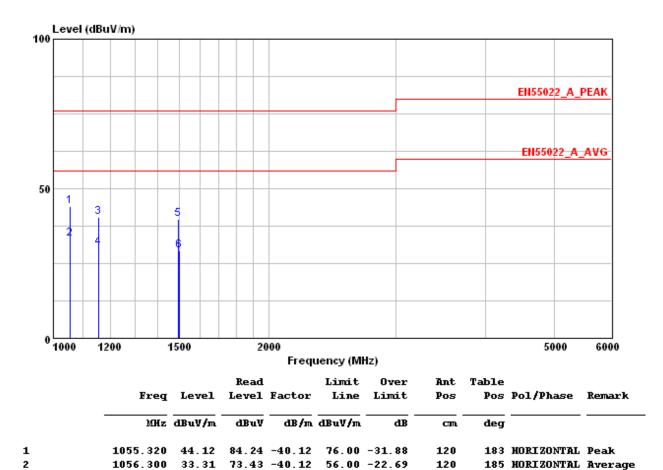
Test Mode : Normal

**Test Voltage**: 230V/50Hz to the power adapter

**Tester**: Carl **Temperature**: 26°C

Humidity: 70%RH Frequency Range: 1GHz~6GHz

IF Bandwidth: 1MHz Polarization: Horizontal



80.49 -40.00 76.00 -35.51

79.75 -40.05 76.00 -36.30

56.00 -25.69

#### Note:

1. Emission Level = reading value + correction factor.

39.70

2. Correction factor = cable loss + antenna factor – gain of pre-amplifier.

70.31 -40.00

1496.300 29.15 69.20 -40.05 56.00 -26.85

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1155.270 40.49

1156.300 30.31

1495.280

TEL.: 886-2-25984542 FAX.: 886-2-25984546 105 HORIZONTAL Peak

22 HORIZONTAL Peak

108 HORIZONTAL Average

26 HORIZONTAL Average

120

120

120

120

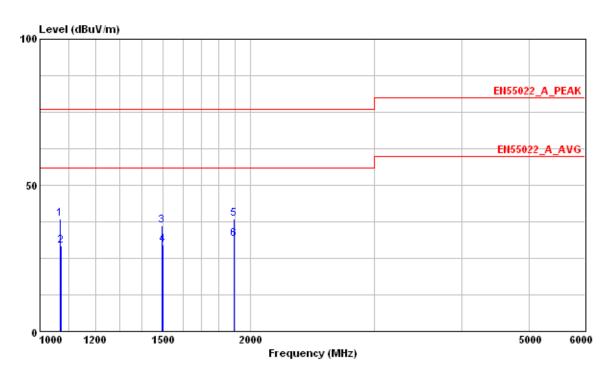
Test Mode : Normal

**Test Voltage**: 230V/50Hz to the power adapter

**Tester**: Carl **Temperature**: 26°C

**Humidity**: 70%RH **Frequency Range**: 1GHz~6GHz

IF Bandwidth: 1MHz Polarization: Vertical



	Freq	Level	Read Level	Factor	Limit Line	Over Limit	Ant Pos	Table Pos	Pol/Phase	Remark
	MHz	dBuV/m	dBuV	dB/m	dBuV/m	dB	cm	deg		
1	1070.300	38.63	78.76	-40.13	76.00	-37.37	120	112	VERTICAL	Peak
2	1071.600	29.17	69.30	-40.13	56.00	-26.83	120	114	VERTICAL	Average
3	1495.600	36.23	76.28	-40.05	76.00	-39.77	120	176	VERTICAL	Peak
4	1496.400	29.66	69.71	-40.05	56.00	-26.34	120	174	VERTICAL	Average
5	1890.600	38.62	75.30	-36.68	76.00	-37.38	120	9	VERTICAL	Peak
6	1891.400	31.52	68.20	-36.68	56.00	-24.48	120	5	VERTICAL	Average

#### Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.

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### 4. Harmonic Current Emission Measurement

Test Result : PASS

#### 4.1 Limits for Emission Measurement

☑ Limits for Class A equipment

Maximum permissible	Harmonic order (n)	Maximum permissible
harmonic current (A)	Even Harmonics	harmonic current (A)
2.30	2	1.08
1.14	4	0.43
0.77	6	0.3
0.40	8 ≦ n ≦40	0.23 8/n
0.33		
0.21		
0.15 15/n		
	2.30 1.14 0.77 0.40 0.33 0.21	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$

# ☐ Limits for Class B equipment

It shall not exceed the vales give in calss A multiplied by a factor of 1.5.

☐ Limits for Class C equipment

Harmonic order (n)	Maximum permissible harmonic current expressed as a percentage of the input current at the fundamental frequency %			
2	2			
3	30·λ (λ is the circuit power factor)			
5	10			
7	7			
9	5			
11 ≤ n ≤ 39	3			
(odd harmonics only)				

☐ Limits for Class D equipment

Harmonic order (n)	Maximum permissible harmonic	Maximum permissible harmonic
Trannonic order (ii)	current per watt (mA/W)	current (A)
3	3.4	2.30
5	1.9	1.14
7	1.0	0.77
9	0.5	0.40
11	0.35	0.33
13 ≤ n ≤ 39	3.85/n	See class A
(odd harmonics only)		

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#### **Test Instruments** 4.2

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Wandacturer	Serial No.	<b>Calibration Date</b>	Due Date	
Power Source		5001ix-208/	Oct. 17, 2012	Oct 17 2012	
Power Source	California	56619	OCI. 17, 2012	Oct. 17, 2013	
Power Analyzer	Instrument	PACS-1/	Oct. 17, 2012	Oct. 17, 2013	
Powei Analyzei		72398	OCI. 17, 2012		
Test Software	C.I.	CTS 3.0/	NCR	NCR	
Test Software	C.I.	Ver. 3.2.0.18	NCR		
TR7	ETS.	TR7/	NCR	NCR	
shielded room	LINDGREN	15353-D	INCR	NCR	

#### Note:

- The calibrations are traceable to NML/ROC.
- NCR: No Calibration Required. 2.

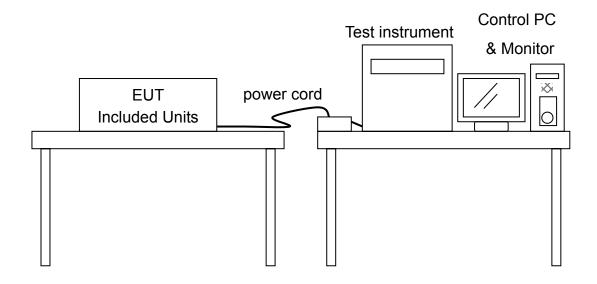
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#### 4.3 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters in the shielded room.
- d. Decide the classification of the EUT as following:
  - Class A: balanced three-phase equipment
    - household appliances, excluding equipment identified as class D
    - tools, excluding portable tools
    - dimmers for incandescent lamps
    - audio equipment
    - equipments not specified in one of the three other classes
  - Class B: portable tools
    - arc welding equipment which is not professional equipment.
  - Class C: lighting equipment
  - Class D: Equipment specified power less than or equal to 600W of the following types
    - personal computers and personal computer monitors
    - television receivers
- e. Connects the EUT's power source to the mains power supplied by the test instrument. Turn on the EUT.
- f. Operating the EUT as required and measuring the harmonic current emissions on the current carrying lines of EUT's power source.

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# 4.4 Test Configurations



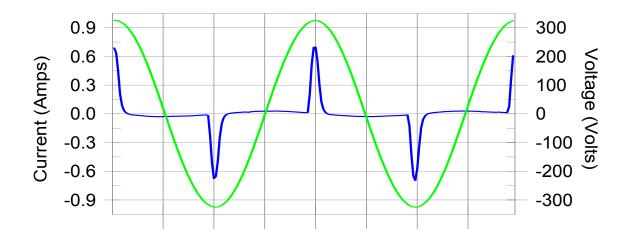
# 4.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

#### **Test Results** 4.6

**Test Mode** Normal **Tester** Mathew 27°C **Temperature** Humidity 73%RH

TEST FREQ	50
TEST VOLTS	230
TEST TIME	10 Minutes
MAX WATTS	19.4 W



The EUT power level is below 75.0 Watts and therefore has no defined limits.

#### **Test Raw Data:**

Harm#	Harms(avg)	100%Limit	%of Limit	Harms(max)	150%Limit	%of Limit	Status
2	0.001	1.080	0.1	0.001	1.620	0.09	N/L
3	0.078	2.300	3.4	0.079	3.450	2.29	N/L
4	0.001	0.430	0.2	0.001	0.645	0.17	N/L
5	0.071	1.140	6.2	0.072	1.710	4.21	N/L
6	0.001	0.300	0.2	0.001	0.450	0.16	N/L
7	0.062	0.770	8.1	0.063	1.155	5.48	N/L
8	0.001	0.230	0.2	0.001	0.345	0.18	N/L
9	0.053	0.400	13.2	0.054	0.600	8.94	N/L
10	0.000	0.184	0.3	0.001	0.276	0.21	N/L
11	0.043	0.330	13.1	0.044	0.495	8.85	N/L
12	0.000	0.153	0.3	0.001	0.230	0.27	N/L
13	0.034	0.210	16.2	0.035	0.315	10.95	N/L
14	0.000	0.131	0.0	0.000	0.197	0.23	N/L
15	0.026	0.150	17.2	0.026	0.225	11.62	N/L
16	0.000	0.115	0.0	0.000	0.173	0.24	N/L
17	0.019	0.132	14.2	0.019	0.199	9.49	N/L
18	0.000	0.102	0.0	0.000	0.153	0.28	N/L
19	0.013	0.118	10.8	0.013	0.178	7.26	N/L
20	0.000	0.092	0.0	0.000	0.138	0.22	N/L
21	0.008	0.107	7.5	800.0	0.161	5.11	N/L
22	0.000	0.084	0.0	0.000	0.125	0.21	N/L
23	0.005	0.098	4.7	0.005	0.147	3.25	N/L
24	0.000	0.077	0.0	0.000	0.115	0.22	N/L
25	0.003	0.090	2.9	0.003	0.135	1.97	N/L
26	0.000	0.071	0.0	0.000	0.106	0.20	N/L
27	0.002	0.083	2.7	0.002	0.125	1.83	N/L
28	0.000	0.066	0.0	0.000	0.099	0.23	N/L
29	0.003	0.078	3.4	0.003	0.116	2.33	N/L
30	0.000	0.061	0.0	0.000	0.092	0.27	N/L
31	0.003	0.073	3.9	0.003	0.109	2.68	N/L
32	0.000	0.058	0.0	0.000	0.086	0.23	N/L
33	0.003	0.068	4.1	0.003	0.102	2.80	N/L
34	0.000	0.054	0.0	0.000	0.081	0.20	N/L
35	0.002	0.064	3.9	0.003	0.096	2.63	N/L
36	0.000	0.051	0.0	0.000	0.077	0.21	N/L
37	0.002	0.061	3.3	0.002	0.091	2.27	N/L
38	0.000	0.048	0.0	0.000	0.073	0.20	N/L
39	0.001	0.058	2.6	0.002	0.087	1.76	N/L
40	0.000	0.046	0.0	0.000	0.069	0.22	N/L

### 5. Voltage Fluctuations and Flickers Emission Measurement

Test Result : PASS

#### 5.1 Limits for Emission Measurement

- the short-term flicker indicator, P<sub>st</sub>, shall not be greater than 1.0;
- the long-term flicker indicator, P<sub>lt</sub>, shall not be greater than 0.65;
- the relative steady-state voltage change, d<sub>c</sub>, shall not exceed 3.3%;
- the voltage change with time, d(t), during a voltage change shall not exceed 3.3% for more than 500ms.
- the maximum relative voltage change, d<sub>max</sub>, shall not exceed
  - ☑ a) 4% without additional conditions;
  - □ b) 6% for equipment which is switched manually
  - □ c) 7% for equipment which is attended whilst in use

#### 5.2 Test Instruments

Test Site and	Manufacturer	Model No./	Last	Calibration
Equipment	Manufacturer	Serial No.	<b>Calibration Date</b>	Due Date
Power Source	California	5001ix-208/ 56619	Oct. 17, 2012	Oct. 17, 2013
Power Analyzer	Instrument	PACS-1/ 72398	Oct. 17, 2012	Oct. 17, 2013
Test Software	C.I.	CTS 3.0/ Ver. 3.2.0.18	NCR	NCR
TR7 shielded room	ETS. LINDGREN	TR7/ 15353-D	NCR	NCR

#### Note:

1. The calibrations are traceable to NML/ROC.

2. NCR : No Calibration Required.

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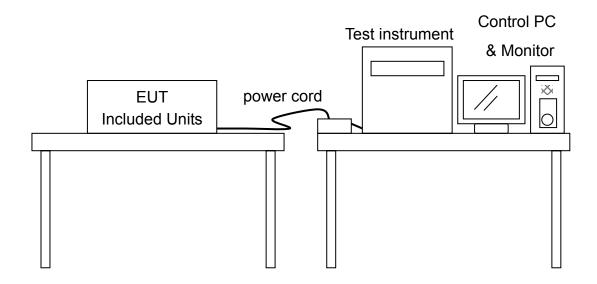
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#### **Test Procedures** 5.3

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters in the shielded room.
- d. Decide the type of EUT to define the d<sub>max</sub> limit and its corresponding test methods described in the relative standard.
- e. Maintain the supply voltage to be ±2% of the EUT's rated voltage and also the frequency to be 50Hz ±0.5%.
- f. Connects the EUT's power source to the mains power supplied by the test instrument.
- g. Operating the EUT as required and measuring the voltage fluctuation and flickers of EUT's power source.
- h. Verify the fluctuations of the test supply voltage to be less than 0.4 before and after the test.

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# 5.4 Test Configurations



# 5.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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#### **5.6 Test Results**

**Test Mode** Normal **Tester** Mathew

27°C **Temperature** 

**Humidity** 73%RH

TEST FREQ	50			
TEST VOLTS	230	230		
TEST TIME	10 Minutes	10 Minutes		
	EUT Data	Limit		
d(t)>3.3% (ms)	0	500		
d <sub>c</sub> (%)	0	3.3		
d <sub>max</sub> (%)	0	4		
P <sub>st</sub> max	0.064	1		
P <sub>lt</sub> max	0.028	0.65		



# 6. Electrostatic Discharge (ESD) Immunity Test

Test Result : PASS

### 6.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : EN 55024:2010

**Basic Standard** : EN 61000-4-2:2009

Required Performance : B

**Test Level** : 2 (Contact discharge)

3 (Air discharge)

**Discharge Voltage** : Contact →±4kV (Direct / Indirect discharge)

Air  $\rightarrow \pm 2kV$ ,  $\pm 4kV$ ,  $\pm 8kV$  (Direct discharge)

Time Interval : 1 sec. minimum

Number of discharges : Minimum 20 times at each test point

**Test Voltage** : 230V/50Hz to the power adapter

Tester : Rick
Ambient Temperature : 21°C
Relative Humidity : 48%

**Atmospheric Pressure** : 1022mbar

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### 6.2 Description of Performance Criteria

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

normal performance, without operator intervention;

Criteria C: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

**Criteria D**: loss of function or degradation of performance which is not recoverable,

owing to damage to hardware or software, or loss of data.

#### 6.3 Test Instruments

Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date
Electrostatic Generator	EM TEST	DITO/ V1138110834	Dec. 25, 2012	Dec. 25, 2013
TR8 shielded room	ETS. LINDGREN	TR8/ 15353-C	NCR	NCR

#### Note:

1. The calibrations are traceable to NML/ROC.

2. NCR: No Calibration Required.

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#### 6.4 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters above the ground reference plane in the shielded room. Also a HCP (Horizontal Coupling Plane) which was connected to the ground reference plane via a cable with a 470kΩ resister located at each end was placed on the wooden table and isolated with the EUT by an insulating support 0.5mm thick. The ground reference plane shall project beyond the EUT or HCP by at least 0.5m on all sides.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room. The ground reference plane shall project beyond the EUT by at least 0.5m on all sides.
- d. Keep the EUT 1m away from all other metallic walls in the shielded room as the minimum distance.
- e. The static electricity discharges shall be applied only to those points and surfaces of the EUT which are accessible to persons during normal use. Contact discharge is the preferred test method and it is applied to the conductive surfaces of EUT and coupling planes. Air discharge shall be used where contact discharge cannot be performed and it is applied to the insulating surfaces of EUT.
- f. The discharge return cable of the generator shall be kept at a distance of at least 0.2m from the EUT whilst the discharge is being applied.
- g. The time interval between successive single discharges was at least 1 second.
- h. Select appropriate points of the EUT for contact discharge and put marks on it to indicate the tested point(s). Then start the contact discharge with the tip of the discharge electrode to touch the EUT before the discharge switch is operated.
- i. Use the round discharge tip of the discharge electrode to scan the EUT to select the points for air discharge. Then start the air discharge by approaching the discharge electrode as fast as possible to touch the EUT. After each discharge, the ESD generator shall be removed from the EUT.
- j. The indirect HCP discharge test is applied at the front edge of each HCP opposite the center point of each unit of the EUT and 0.1m from the front of the EUT. The long axis of the discharge electrode shall be in the plane of the HCP and perpendicular to its front edge during the discharge.

11, Lane 41, Fushuen St., Jungs TEL.: 886-2-25984542 k. The indirect VCP (Vertical Coupling Plane) discharge test is applied to the center of one vertical edge of the coupling plane. The VCP, of dimensions 0.5m×0.5m, is placed parallel to, and positioned at a distance of 0.1m from the EUT. It shall be applied with sufficient different positions such that the four faces of the EUT are completely illuminated.

# Special Test Requirements for Information Technology Equipment (ITE)

The discharges shall be applied in two ways as below:

a. Contact discharges to the conductive surfaces and coupling planes:

The EUT shall be exposed to at least 200 discharges, 100 each at negative and positive polarity, at a minimum of four test points. One of the test points shall be subjected to at least 50 indirect discharges to the center of the front edge of the horizontal coupling plane. The remaining three test points shall each receive at least 50 direct contact discharges. If no direct contact test points are available, at least 200 indirect discharges shall be applied in the indirect mode (for use of the VCP).

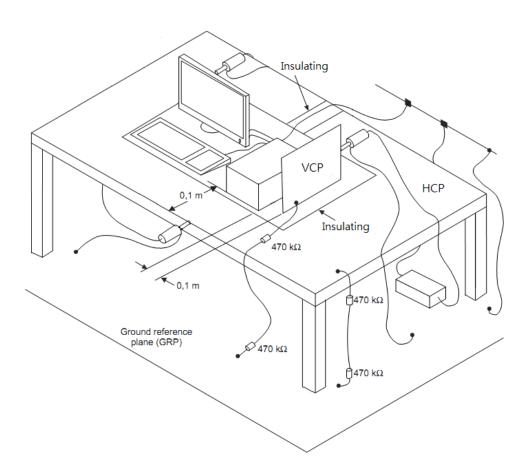
b. Air discharges at slots and apertures and insulating surfaces:

A minimum of 10 single air discharges shall be applied to the each selected test point.

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# 6.5 Test Configurations



# 6.6 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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### 6.7 Test Results

Test Mode : Normal

Discharge	Type of	Label for	Perfo	rmance	Result
Voltage (kV)	discharge	Dischargeable Points	Required	Observation	
±4	Contact	5~9	В	A(1)	Pass
±2	Air	1~4	В	A(1)	Pass
±4	Air	1~4	В	A(1)	Pass
±8	Air	1~4	В	A(1)	Pass
±4	HCP-Bottom	Edge of the HCP	В	A(1)	Pass
±4	VCP-Front	Center of the VCP	В	A(1)	Pass
±4	VCP-Left	Center of the VCP	В	A(1)	Pass
±4	VCP-Back	Center of the VCP	В	A(1)	Pass
±4	VCP-Right	Center of the VCP	В	A(1)	Pass

# **Observation of Performance during Test**

(1) Normal operation condition specified by manufacturer during the test.

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# Photographs of the Dischargeable Points on the EUT for ESD Test











## 7. Radiated Electromagnetic Field (RS) Immunity Test

Test Result : PASS

### 7.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : EN 55024:2010

**Basic Standard** : EN 61000-4-3:2006+A1:2008+A2:2010

Required Performance : A

Test Level : 2

Field Strength : 3 V/m

**Test Frequency Range** : 80MHz ~ 1GHz

Frequency Step : 1% of the momentary frequency

Dwell Time : Minimum 3 sec. per frequency

**Modulation** : 1kHz Sine Wave with 80% Amplitude Modulation

**Polarization of Antenna** : Horizontal and Vertical

**Test Voltage** : 230V/50Hz to the power adapter

Tester : Scott

Ambient Temperature : 28°C

Relative Humidity : 60%

**Atmospheric Pressure** : 1010mbar

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## 7.2 Description of Performance Criteria

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

normal performance, without operator intervention;

**Criteria C**: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

**Criteria D**: loss of function or degradation of performance which is not recoverable,

owing to damage to hardware or software, or loss of data.

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#### 7.3 Test Instruments

Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date
Signal Generator	R&S	SML03/ 101676	July 12, 2012	July 12, 2013
Switch Box	AR	SC1000M3/ 309064	NCR	NCR
Dual Directional	AR	DC6180/ 28730	Jan. 3, 2013	Jan. 3, 2014
Coupler	AR	DC 7144A/ 308731	May 7, 2013	May 7, 2014
Power	AR	150W1000/ 29167	NCR	NCR
Amplifier	AR	30S1G3/ 308785	NCR	NCR
	EMCO	3142B/ 1716	NCR	NCR
Bi-Log Antenna	R&S	HL046/ 359132/004	NCR	NCR
	TRC	TRC Horn/ 001	NCR	NCR
Field Monitor	AR	FM7004/ 0336364	NCR	NCR
Electric Field Probe	AR	FL7006/ 0336500	April 16, 2013	April 16, 2014
Probe Positioner	HD	FSM916/ 916/319	NCR	NCR
Controller	HD	HD100/ 100/671	NCR	NCR
Dual Channel Power Meter	R&S	NRVD/ 100499	Jan. 4, 2013	Jan. 4, 2014
Test Software	AR	SW1007/ Ver. 2.0.1	NCR	NCR
TR2 fully- anechoic chamber	ETS. LINDGREN	TR2/ 15353-R	Sept. 16, 2012	Sept. 16, 2013

#### Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.
- 3. The calibration date of the fully-anechoic chamber listed above is the date of Field Uniformity Calibration measurement.

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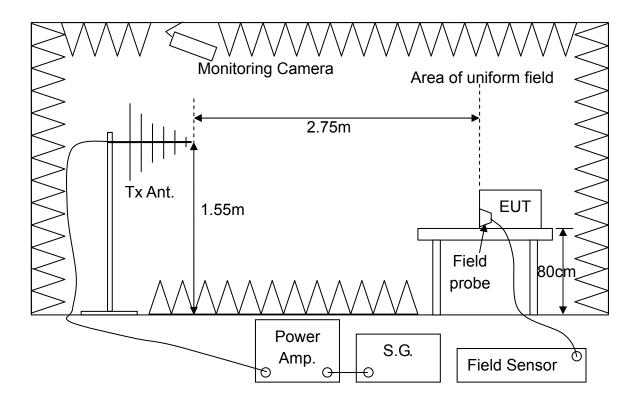
#### 7.4 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters and 2.75 meters away from the transmitting antenna in the fully anechoic chamber.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters and 2.75 meters away from the transmitting antenna in the fully anechoic chamber. Also if the floor-standing equipment which is capable of being stood on a non-conducting 0.8m high platform may be so arranged.
- d. All EUT's individual faces shall be fully enclosed by the "uniform area" and its wires shall be arranged parallel to the uniform area of the field.
- e. Before testing the EUT, the intensity of the established field strength is checked by placing the field sensor at a calibration grid point to give the calibrated field strength to measure the EUT.
- f. After the calibration has been verified, the test field can be generated using the values obtained from the calibration.
- g. Perform the test with the specified immunity level in the test frequency range and with the specified modulation type.
- h. The transmitting antenna is normally facing each of the four sides of the EUT with two polarizations (Vertical and Horizontal) to perform the test.
- i. The dwell time at each frequency shall be not less than the time necessary for the EUT to be exercised and be able to respond.
- j. The sensitive frequencies of EUT shall be analyzed separately, if any.
- k. Record the performance of the EUT.

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# 7.5 Test Configurations



# 7.6 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

### 7.7 Test Results

Test Mode : Normal

Side of the EUT	Polarization	Perfo	Result	
Side of the Eof	Polarization	Required	Observation	(Pass/Fail)
Front	Н	Α	A(1)	Pass
	V	Α	A(1)	Pass
Left	Н	Α	A(1)	Pass
	V	Α	A(1)	Pass
Back	Н	Α	A(1)	Pass
	V	Α	A(1)	Pass
Right	Н	Α	A(1)	Pass
	V	Α	A(1)	Pass

# **Observation of Performance during Test**

(1) Normal operation condition specified by manufacturer during the test.

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## 8. Electrical fast transient / burst (EFT) Immunity Test

Test Result : PASS

### 8.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : EN 55024:2010

**Basic Standard** : EN 61000-4-4:2004+A1:2010

Required Performance : B
Test Level : 2

Voltage Peak : ☑ ±1kV (on power supply port)

☑ ±0.5kV (on I/O signal, data and control port)

**Impulse Frequency**: 5kHz

Wave Shape of the Pulse  $(T_r/T_h)$ : 5ns / 50ns

Burst Duration : 15ms
Burst Period : 300ms
Time Duration : 1 min

**Test Voltage** : 230V/50Hz to the power adapter

Tester : Mathew

Ambient Temperature : 27°C

Relative Humidity : 43%

**Atmospheric Pressure** : 1010mbar

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## 8.2 Description of Performance Criteria

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

normal performance, without operator intervention;

Criteria C: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

**Criteria D**: loss of function or degradation of performance which is not recoverable,

owing to damage to hardware or software, or loss of data.

#### 8.3 Test Instruments

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Manuacturei	Serial No.	Calibration Date	Due Date	
EFT/Burst	EMC PARTNER	TRA2000IN6/	April 2, 2013	April 2, 2014	
Simulator	EWIC PARTNER	870	April 2, 2013		
Coupling	EMC PARTNER	CN-EFT1000/	NCR	NCR	
Clamp	EWIC PARTNER	532	NCR		
Test Software	EMC PARTNER	TEMA/	NCR	NCR	
lest Software	EWIC PARTNER	Ver. 1.86	NCR		
TR7	ETS.	TR7/	NCR	NCR	
shielded room	LINDGREN	15353-D	NOR		

Note:

1. The calibrations are traceable to NML/ROC.

NCR : No Calibration Required.

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### 8.4 Test Procedures

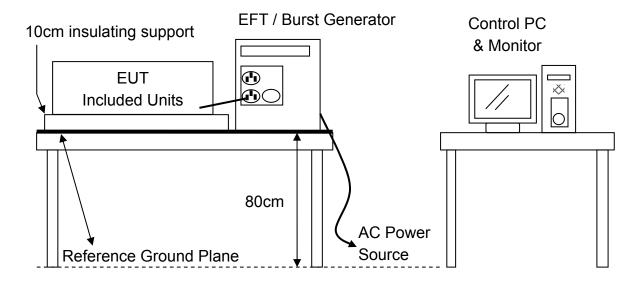
- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted support with a height 0.1 meters above the ground reference plane. Also the ground reference plane is placed on a wooden table with a height of 0.8 meters in the shielded room. The ground reference plane shall project beyond the EUT by at least 0.1m on all sides.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room. The ground reference plane shall project beyond the EUT by at least 0.1m on all sides.
- d. The test generator and the coupling/decoupling network shall be placed directly on, and bonded to, the ground reference plane.
- e. All cables to the EUT shall be placed on the insulation support 0.1 m above the ground reference plane. Cables not subject to electrical fast transients shall be routed as far as possible from the cable under test to minimize the coupling between the cables.
- f. Keep the EUT 0.5m away from all other conductive structures, except the ground reference plane beneath the EUT as the minimum distance. Also if any, the minimum distance between the coupling clamp and all other conductive structures, except the ground reference plane beneath the coupling clamp and EUT shall be 0.5m.
- g. Keep the length of the power and signal lines, if required, between the coupling device and the EUT to be 0.5m. If a non-detachable supply cable more than 0.5m long, the excess length of this cable shall be folded to avoid a flat coil and situated at a distance of 0,1 m above the ground reference plane.
- h. Connect the EUT's power source to the appropriate power through the coupling devices and perform the specified test level.
- If any, connect all the I/O signal, data and control lines between EUT and accessories/support units through the coupling devices and perform the specified test level.
- j. Record the performance of the EUT.

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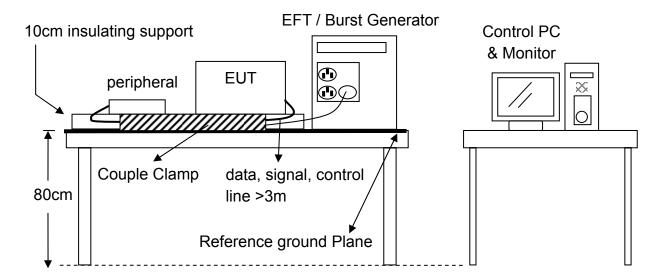
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# 8.5 Test Configurations

## **Power supply port Test**



# I/O signal, data and control port Test (if any)



# 8.6 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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### 8.7 Test Results

Test Mode : Normal

Injected Line	Voltage Peak	Injected	Perfo	Result	
i injected Line	(kV)	Method	Required	Observation	(Pass/Fail)
L1 - L2 - PE	±1.0	Direct	В	A(1)	Pass
Data Line (RJ-45)	±0.5	Clamp Coupling	В	A(1)	Pass

# **Observation of Performance during Test**

(1) Normal operation condition specified by manufacturer during the test.

# 9. Surge Immunity Test

Test Result : PASS

## 9.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : EN 55024:2010

**Basic Standard** : EN 61000-4-5:2006

Required Performance : B

**Test Level** : ☑ 2 (line to line on power supply port)

☑ 3 (line to earth (ground) on power supply port)

☐ 2 (on I/O signal, data and control port)

**Open-circuit Test Voltage** :  $\boxtimes \pm 0.5$ kV,  $\pm 1$ kV (line to line on power supply port)

☑ ±0.5kV, ±1kV, ±2kV (line to earth (ground) on

power supply port)

 $\Box$  ±0.5kV, ±1kV

(on I/O signal, data and control port)

**CW Waveform (T\_r/T\_h)** : 1.2 / 50µs (open-circuit voltage)

8 / 20µs (short-circuit current)

Phase Angel / Reference : 0°, 90°, 180°, 270° / L1

Repetition Rate : 1/min. maximum

Number of Test : at least 5 positive and 5 negative at selected points

**Test Voltage** : 230V/50Hz to the power adapter

Tester : Mathew

Ambient Temperature : 27°C

**Relative Humidity** : 73%

**Atmospheric Pressure** : 1010mbar

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### 9.2 Description of Performance Criteria

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

normal performance, without operator intervention;

Criteria C: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

**Criteria D**: loss of function or degradation of performance which is not recoverable,

owing to damage to hardware or software, or loss of data.

#### 9.3 Test Instruments

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Manuacturer	Serial No.	<b>Calibration Date</b>	Due Date	
Surge	EMC PARTNER	TRA2000IN6/	April 2, 2013	April 2, 2014	
Simulator		870	, .p =, =0 : 0		
Telecom	KeyTek	CM-TELCD/	June 9, 2010	June 9, 2013	
Coupler	Reylek	0103215	Julie 9, 2010		
Test Software	EMC PARTNER	TEMA/	NCR	NCR	
Test Software	LIVIC PAINTINEIX	Ver. 1.86	NOIX		
TR7	ETS.	TR7/	NCR	NCR	
shielded room	LINDGREN	15353-D	NOR		

Note:

1. The calibrations are traceable to NML/ROC.

2. NCR: No Calibration Required.

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#### 9.4 Test Procedures

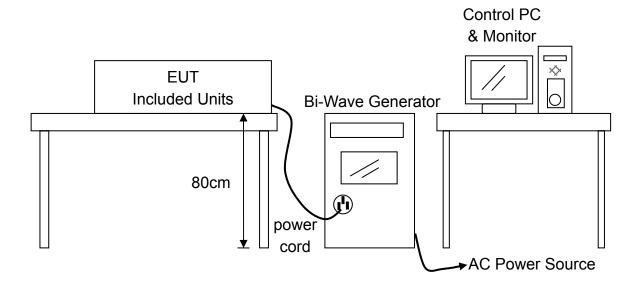
- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room.
- d. For the surge test applied to EUT's power supply and unshielded unsymmetrical interconnection lines, if required, the capacitive coupling network are used.
- e. If any, the surge test applied to the unshielded symmetrically interconnection lines of EUT, the gas arrestors coupling network are used.
- f. Keep the interconnection line, if required, or power cord between the EUT or its power source and the coupling / decoupling network to be 2m in length (or shorter).
- g. The surges have to be applied synchronized to the voltage phase at the zero-crossing and the peak value of the a.c. voltage wave (positive and negative).
- h. All lower levels including the selected test level shall be satisfied and the test voltage has to be increased by steps up to the specified test level.
- i. Connect the EUT's power source to the appropriate power through the coupling devices and perform the specified test level.
- j. If any, connect all the interconnection lines between EUT and accessories/support units through the coupling devices and perform the specified test level.
- k. Record the performance of the EUT.

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#### **Test Configurations** 9.5



#### 9.6 **Photographs of the Test Configurations**

Please refer to the Attachment 1 of the present report.

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### 9.7 Test Results

Test Mode : Normal

	Open-circuit	Performance				Result	
Coupled Line	Test Voltage	Doguirod	Observation			(Pass/Fail)	
	(kV)	Required	0°	90°	180°	270°	(Fass/Faii)
L1 - PE	±0.5	В	A(1)	A(1)	A(1)	A(1)	Pass
L2 - PE	±0.5	В	A(1)	A(1)	A(1)	A(1)	Pass
L1 – L2	±0.5	В	A(1)	A(1)	A(1)	A(1)	Pass
L1 - PE	±1	В	A(1)	A(1)	A(1)	A(1)	Pass
L2 - PE	±1	В	A(1)	A(1)	A(1)	A(1)	Pass
L1 – L2	±1	В	A(1)	A(1)	A(1)	A(1)	Pass
L1 - PE	±2	В	A(1)	A(1)	A(1)	A(1)	Pass
L2 - PE	±2	В	A(1)	A(1)	A(1)	A(1)	Pass

# **Observation of Performance during Test**

(1) Normal operation condition specified by manufacturer during the test.

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## 10. Conducted disturbances (CS) Immunity Test

Test Result : PASS

## 10.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : EN 55024:2010

**Basic Standard** : EN 61000-4-6:2009

Required Performance : A

Test Level : 2

**Voltage Level(e.m.f.)** : 3V (e.m.f.)

**Test Frequency Range** : 150kHz ~ 80MHz

Frequency Step : 1% of the momentary frequency

Dwell Time : Minimum 3 sec. per frequency

**Modulation** : 1kHz Sine Wave with 80% Amplitude Modulation

**Coupling Devices** : ☑ CDN-M3 (on power supply port)

: ☐ CDN-T2 (on RJ-11 port)

☐ CDN-T4 (on LAN port)

☑ CDN-T8 (on LAN port)

☐ EM Clamp (on I/O signal, data and control port)

**Test Voltage** : 230V/50Hz to the power adapter

Tester : Scott

**Ambient Temperature** : 25°C

**Relative Humidity** : 66%

**Atmospheric Pressure** : 1010mbar

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## 10.2 Description of Performance Criteria

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

normal performance, without operator intervention;

**Criteria C**: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

**Criteria D**: loss of function or degradation of performance which is not recoverable,

owing to damage to hardware or software, or loss of data.

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## 10.3 Test Instruments

Test Site and Equipment	Manufacturer		Model No./ Serial No.	Last Calibration Date	Calibration Due Date
Signal Generator	R&S		SML03/ 101676	July 12, 2012	July 12, 2013
Dual Directional Coupler	AR		DC2600/ 28834	Jan. 3, 2013	Jan. 3, 2014
Power Amplifier	AR		75A250/ 28845	NCR	NCR
			FCC-801-M2-16A/ 2032	Jan. 14, 2013	Jan. 14, 2014
	FCC	$\mathbf{\Sigma}$	FCC-801-M3-16A/ 2060	Jan. 14, 2013	Jan. 14, 2014
CDN			FCC-801-M5-16A/ 2020	Jan. 14, 2013	Jan. 14, 2014
02.1			FCC-801-T2/ 2032	Sept. 5, 2012	Sept. 5, 2013
			FCC-801-T4-RJ45/ 08031	Sept. 5, 2012	Sept. 5, 2013
		V	NCDN-T8-RJ45/ 06016	March 16, 2013	March 16, 2014
EM CLAMP	FCC	Ī	FCC-203I-23MM/ 107	Jan. 4, 2013	Jan. 4, 2014
Test Software	AR		SW1006/ Ver. 1.13	NCR	NCR
AR shielded room	ETS. LINDGREN		AR/ 15353-J	NCR	NCR

#### Note:

1. The calibrations are traceable to NML/ROC.

2. NCR: No Calibration Required.

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#### 10.4 Test Procedures

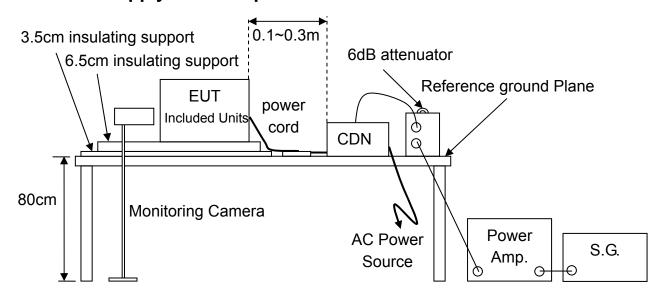
- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted support with a height 0.1 meters above the ground reference plane. Also the ground reference plane is placed on a wooden table with a height of 0.8 meters in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room.
- d. Decide the injection methods and test points according to the relative standard.
- e. All relevant cables shall be provide with the appropriate coupling and decoupling devices at a distance between 0.1m and 0.3m from the projected geometry of the EUT on the ground reference plane.
- f. All cables connected to each Auxiliary Equipment (AE), other than those being connected to the EUT, shall not be bundled nor wrapped and shall be kept between 30mm and 50mm above the ground reference plane.
- g. The test shall be performed with the test generator connected to each of the coupling and decoupling devices in turn while the other non-excited RF input ports of the coupling devices are terminated by a  $50\Omega$  load resistor.
- h. Perform the test with the specified immunity level in the test frequency range and with the specified modulation type.
- i. The dwell time at each frequency shall be not less than the time necessary for the EUT to be exercised and be able to respond.
- j. The sensitive frequencies of EUT and harmonics or frequencies of dominant interest shall be analyzed separately, if any.
- k. Record the performance of the EUT.

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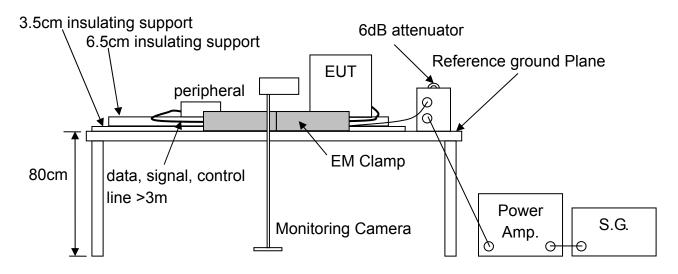
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## 10.5 Test Configurations

## **Power supply and LAN port Test**



## I/O signal, data and control port Test (if any)



## 10.6 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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## 10.7 Test Results

Test Mode : Normal

Injected Line	Coupling Devices	Perfo	Result	
injected Line	Coupling Devices	Required	Observation	(Pass/Fail)
Power Lines	CDN-M3	Α	A(1)	Pass
Data Line (RJ-45)	CDN-T8(1Gbps)	Α	A(1)	Pass

# **Observation of Performance during Test**

(1) Normal operation condition specified by manufacturer during the test.

## 11. Power frequency magnetic field (PFM) Immunity Test

Test Result : PASS

## 11.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : EN 55024:2010

**Basic Standard** : EN 61000-4-8:2010

Required Performance : A

Test Level : 1

Magnetic Field Strength : 1 A/m

Power Frequency : 50 Hz
Test Duration : 1 min.

**Magnetic Field Orientation** : X, Y, Z-axis

**Test Voltage** : 230V/50Hz to the power adapter

Tester : Mathew

**Environment Magnetic Field:** 0.05 A/m (< 0.1 A/m (20dB below the test field))

Ambient Temperature : 26°C

Relative Humidity : 69%

**Atmospheric Pressure** : 1010mbar

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## 11.2 Description of Performance Criteria

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

normal performance, without operator intervention;

Criteria C: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

**Criteria D**: loss of function or degradation of performance which is not recoverable,

owing to damage to hardware or software, or loss of data.

#### 11.3 Test Instruments

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Serial No. Ca		Calibration Date	Due Date	
Current	FCC	F-1000-4-8-125A/	June 25, 2012	June 25, 2013	
Source	FCC	1008	Julie 25, 2012		
Coil	FCC	F-1000-4-8-1M/	June 25, 2012	June 25, 2013	
Coll	FCC	1007	June 25, 2012	Julie 25, 2013	
Low Frequency	CHAUVIN	C.A40/	July 10, 2012	July 10, 2012	
Gauss Meter	ARNOUX	150361	July 19, 2012	July 19, 2013	
TR12					
Plane Grounding	CRC	TR12	NCR	NCR	
Site					

#### Note:

1. The calibrations are traceable to NML/ROC.

2. NCR: No Calibration Required.

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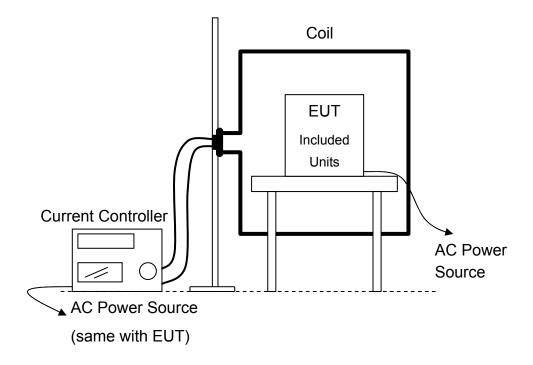
#### 11.4 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height 0.8 meters.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane (minimum size is 1m×1m) in the shielded room.
- d. For the tabletop equipment, the induction coil with a square form in 1m side (or diameter) is used and shall enclose the EUT placed at its center. For the floorstanding equipment, the induction coil shall be able to envelop the EUT and made of conductors of relatively small cross-section.
- e. The dimensions of induction coil shall be able to keep the magnetic fields over the whole volume of the EUT with an acceptable variation of  $\pm 3$ dB.
- f. The test generator shall be placed at less than 3m distance from the induction coil.
- g. Keep all cables of EUT to be exposed to the magnetic field for 1m of their length.
- h. Before the test, maintain the electromagnetic field value of the test environment to be at least 20dB lower than the selected test level. Then tune up the currents of the test generator and use the Guass Meter to calibrate the specified test level at the center of the induction coil.
- i. Perform the test with the specified magnetic field by rotating the induction coil to three different orientations to generate X, Y and Z directed magnetic field sequentially.
- Record the performance of the EUT.

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## 11.5 Test Configurations



## 11.6 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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## 11.7 Test Results

Test Mode : Normal

Magnetic Field	Magnetic Field	Frequency	Performance		Result
Orientation	(A/m)	(Hz)	Required	Observation	(Pass/Fail)
X-axis	1	50	Α	A(1)	Pass
Y-axis	1	50	Α	A(1)	Pass
Z-axis	1	50	Α	A(1)	Pass

# **Observation of Performance during Test**

(1) Normal operation condition specified by manufacturer during the test.

### 12. Voltage dips, short interruptions Immunity Test

Test Result : PASS

## 12.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : EN 55024:2010

**Basic Standard** : EN 61000-4-11:2004

**Required Performance** : ☑ B for 0% residual voltage dips with 0.5 cycle

and Test Level 
☑ C for 70% residual voltage dips with 25

cycles

☐ C for 40% residual voltage dips

☑ C for 0% residual voltage interruptions

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with 250 cycles

**Basis Test Voltage Level (U<sub>T</sub>)** : 230V/50Hz to the power adapter

**Test Duration**: Maximum 3 dips/interruptions with a sequence

Time interval : 10s minimum between each test event

Phase Angle of Abrupt Changes: 0°

Tester : Mathew

Ambient Temperature : 27°C Relative Humidity : 73%

**Atmospheric Pressure** : 1010mbar

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## 12.2 Description of Performance Criteria

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

normal performance, without operator intervention;

Criteria C: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

**Criteria D**: loss of function or degradation of performance which is not recoverable,

owing to damage to hardware or software, or loss of data.

#### 12.3 Test Instruments

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Manufacturer	Serial No.	<b>Calibration Date</b>	Due Date	
Voltage DIP	TRA2000IN6/		April 2 2012	A == :1 0 0044	
Tester	EMC PARTNER	870	April 2, 2013	April 2, 2014	
Test Software	EMC PARTNER	TEMA/	NCR	NCD	
lest Sollware	EIVIC PARTNER	Ver. 1.86	NCR	NCR	
TR7	ETS.	TR7/	NCD	NCD	
shielded room	LINDGREN	15353-D	NCR	NCR	

#### Note:

1. The calibrations are traceable to NML/ROC.

2. NCR: No Calibration Required.

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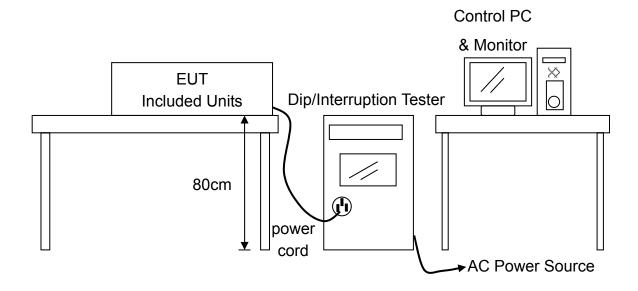
#### 12.4 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height 0.8 meters above the ground reference plane in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room.
- d. The test shall be performed with the EUT connected to the test Generator with the shortest power supply cable as specified by the manufacturer.
- e. If any, tests on the three-phase EUT are accomplished by using three sets of equipment mutually synchronized.
- f. During the tests, the main voltage for testing is monitored within an accuracy of 2% and the zero crossing control of the generators must have an accuracy of  $\pm 10^{\circ}$ .
- g. The EUT shall be tested for each selected combination of test level and duration with a sequence of three dips/interruptions with intervals of 10 sec. minimum (between each test event). Each representative mode of operation shall be test.
- h. Abrupt changes in supply voltage shall occur at zero crossings of the voltage and additional angles preferably selected from 0°, 45°, 90°, 135°, 180°, 225°, 270°, 315° on each phase.
- i. Connect the EUT's power source to the appropriate power through the test generator and perform the specified test level.
- Record the performance of the EUT.

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## 12.5 Test Configurations



## 12.6 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

#### 12.7 Test Results

Test Mode : Normal

## **Voltage Dips Test**

Test level	Reduction	Duration (cycle)	Perfo	Result	
(% residual voltage)	Voltage (%)		Required	Observation	
0	>95	0.5	В	A(1)	Pass
70	30	25	С	A(1)	Pass

## **Voltage Interruption Test**

Test level	Reduction	tage Duration (cvcle)	Perfo	Result	
(% residual voltage)	Voltage (%)		Required	Observation	
0	>95	250	С	C(2)	Pass

## **Observation of Performance during Test**

- (1) Normal operation condition specified by manufacturer during the test.
- (2) The EUT shuts down while test is performing, it can be restarted manually after finishing the test.

# Attachment 1 Photographs of the Test Configurations

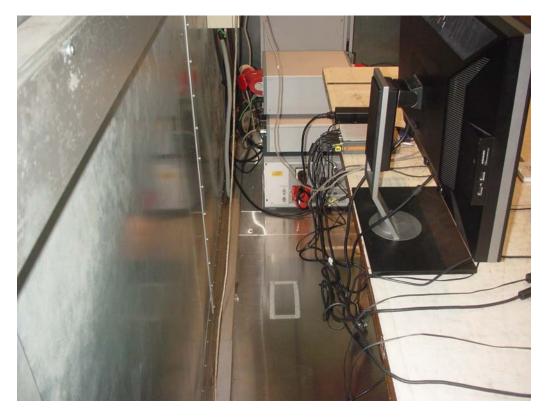
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## 1. Conducted Emission Measurement





## 2. Radiated Emission Measurement





## 3. Harmonic Current & Voltage Fluctuations Emission Measurement



# 4. Electrostatic Discharge (ESD) Immunity Test



# 5. Radiated Electromagnetic Field (RS) Immunity Test



# 6. Electrical fast transient / burst (EFT) Immunity Test



**Test for LAN port** 



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# 7. Surge Immunity Test



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# 8. Conducted disturbances (CS) Immunity Test



**Test for LAN port** 

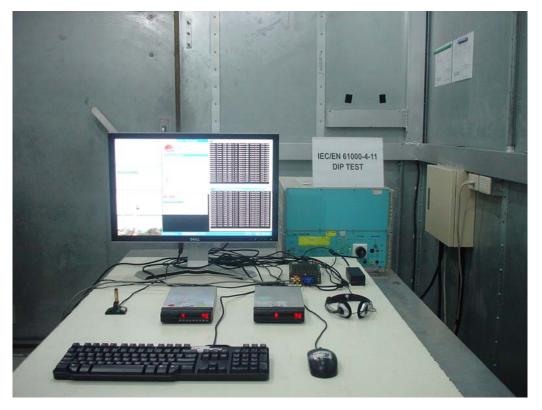


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# Power frequency magnetic field (PFM) Immunity Test



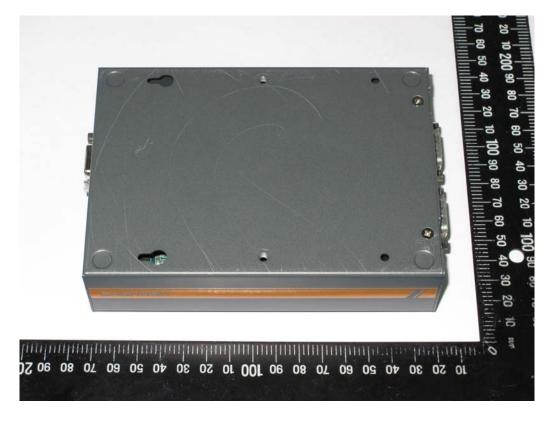
# 10. Voltage dips, short interruptions Immunity Test



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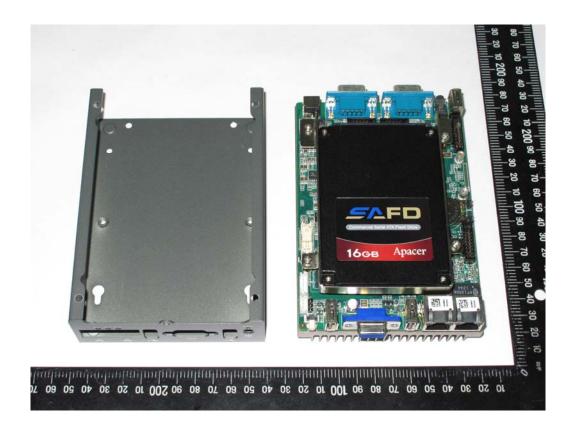
# Attachment 2 Photographs of EUT











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## **Adapter**







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